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### Prior use assessment

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## Vision

Yes No

Creating a better world by making processes safer and more efficient



## Mission

We create value for our customers by making their invisible **process safety risks** and **energy or production losses** visible. This allows targeted actions to be taken to reduce these risks and optimize the plant performance





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### Prior in use assessment

- Safety Lifecycle
- Design
- Proven in use Assessment
- Examples
- Conclusion / discussion



### Safety Lifecycle

- PHA
- Design
- Installation
- Operation/maintenance
- MOC
- Decommissioning



- Selecting parts
  - Proven in use
  - Certified Data
  - Prior use



- Proven in use
  - Data provided by manufacturer
  - Generic information
  - Not according plant situation (service, degradation mechanism, etc)
  - Not officially named in IEC 61511
  - Can be used together with plant information -> prior use



- Certified Data
  - Clear description of failure data
  - Provided installation and safety manual
  - Suitable for both type A and B components
  - Cover all SIL levels
  - No historical data needs to be used to verify component
  - Historical data can be used for validation the application





- Prior use
  - Needs evidence according IEC 61511
  - Using historical data out of the field
  - Suitable for type A and some B components
  - Cover not all SIL levels
  - Used when no certified data is available





- Required evidence according IEC 61511
  - Consideration of the manufacturer's quality, management and configuration management systems
  - Adequate identification and specification of the devices
  - Demonstration of the performance of the devices in similar operating environments
  - The volume of the operating experience
  - Monitoring device performance



- Adequate identification and specification of the devices
  - Proof of manufacturer quality management
  - Availability of operational manual
  - Suitable for both type A and B components
  - For type B also a software assessment is required
  - For higher SIL levels, more evidence is required



- Volume of the operating experience
  - The reliability data uncertainties can be evaluated according to:
    Statistical approaches
    - o Engineering judgement techniques (generic data)
    - o Undertaking specific techniques (like FME(D)A)
  - The amount of field feedback
    - o Less data results in higher uncertainty
    - o Usage of statistical approach
    - o Observation time is only for similar components (size, service, model number



- Use of probabilistic distribution
  - $\chi^2$  distribution: From a sample of n failures observed over a cumulated observation time T the confidence upper bound can be calculated by using the  $\chi^2$  function:  $\lambda_{0.7} = \frac{1}{2T} \chi^2_{0.3,2(n+1)}$
  - Can be used with small size of data
  - Confidence level 70%
  - T = total observation time; n = observed failures



- Observation time (T)
  - Total time (in years) where a component is in service
    - Same model number
    - Same service
    - Same environmental impact
    - Same degradation
  - T ≠ number of component \* service years
    - Replacement
    - Repair
    - MoC



- Use of probabilistic distribution
  - $\chi^2$  vs normal distribution
  - Confidence level 70%



- $\chi^2$  is more conservative and required by IEC 61511
- $\chi^2$  could be 'less required' at large observation time



- $\chi^2$  distribution
  - Reliability (FIT) against
    observation time
  - Different observed events
  - Shows importance of available data

#### $\chi^2$ in relation amount of events



### Prior Use Assessment - examples

• Simple SIF configuration



- Sensor, Logic Solver and Actuator does have valid SIL certificates
  - Sensor: PFD<sub>avg</sub> = 2.85 x 10<sup>-4</sup>
  - Logic Solver:  $PFD_{avg} = 4.82 \times 10^{-4}$
  - Actuator: PFD<sub>avg</sub> = 5.30 × 10<sup>-3</sup>
- Valve doesn't have a valid SIL certificate



- Simple Safety loop
  - High level in tank closes tank-valve
  - All components, except valve, contain necessary certification documents
- Service time plant 18 years
- Total # of valves in service: 90
  - In critical application: 30
  - In process application: 60
- Combines operational service: 500 year
  - Valves in similar service clean
  - Valves within same model number



### Prior in Use Assessment - examples

- Example 1
  - Fictitious vs probabilistic ( $\chi^2$ ) approach
  - Fixed set of results
- Example 2
  - $\chi^2$  approach
  - Lack of maintenance data
- Example 3
  - $\chi^2$  approach
  - Relation between reliability and # events



### Example 1 - results valve

#### • Out of maintenance report, the following data is acquired

Tag #	date	service	failure	Event <sup>1)</sup>	SD	SU	DD	DU	Maintenance	MTTR
XV-003	25-01-99	Clean	Packing leak	Fail safe	1				Packing replacement	45 min
XV-034	04-10-02	Clean	Build up material	Poss. danger			1		Cleaning	1 hour
XV-010	18-08-02	Clean	Shaft damage	Fail to danger				1	Valve replacement	12 hours
XV-150	06-02-09	Clean	Packing leak	Fail safe	1				Packing replacement	1,5 uur
XV-068	19-04-15	Clean	Valve not closed 100%	Poss. Danger			1		Valve replacement	16 hours
XV-099	31-10-19	Clean	Build up material	Poss. Danger			1		Cleaning	30 min

- Proof-test interval (T1) = 8760 hours (1 year)
- MTTR = 5.3 hours (average)

<sup>1)</sup> In relation to functional safety, not process safety



### Example 1 – Fictitious example

- Failure rate [in FIT(Failure in Time)]:
  - **λ** = n / T
  - $\lambda_{DU}$  = 228 FIT;  $\lambda_{DD}$  = 685 FIT;  $\lambda_{SD}$  = 457 FIT;  $\lambda_{D}$  = 913 FIT
- Calculate PFD<sub>avg</sub>
  - PFDavg = 5.36 x 10<sup>-4</sup>



### Example 1 – probabilistic example

- $\chi^2[\alpha/2, 2n+2]; \alpha/2 = 0.3$  (70% confidense, n = amount of events)
- $\lambda = \chi^2/(2 \times T)$
- Failure rate:
  - $\lambda_{DU}$  = 556 FIT;  $\lambda_{DD}$  = 1090 FIT;  $\lambda_{SD}$  = 825 FIT  $\lambda_{D}$  = 856 FIT
- Calculate PFD<sub>avg</sub>
  - PFD<sub>avg</sub> = 2.46 × 10<sup>-3</sup>



- Results prior use calculation:
  - Fictitious approach (prior use): PFD<sub>avg</sub> = 5.36 x 10<sup>-4</sup>
  - Probabilistic approach (prior use): PFD<sub>avg</sub> = 2.46 x 10<sup>-3</sup>
- Total loop results:
  - Fictitious approach: PFD<sub>avg</sub> = 6.60 x 10<sup>-3</sup> -> RRF 151
  - Probabilistic approach: PFD<sub>avg</sub> = 8.53 × 10<sup>-3</sup> -> RRF 117



### Example 2 - results valve

#### • Out of maintenance report the following data is acquired

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- Prooftest interval (T1) = 8760 hours (1 year)
- MTTR = 5.3 hours
- Lack of maintenance data all events considered as dangerous failure

- $\chi^2[\alpha/2, 2n+2]$ ; (70% confidence, n = number of events = 6)
- $\lambda = \chi^2/(2 \times T)$
- Failure rate:
  - $\lambda_{\text{DU}}$  = 185 FIT
- Calculate  $\mathsf{PFD}_{\mathsf{avg}}$  for  $\mathsf{SIF}$ 
  - PFD<sub>avg</sub> = 1.42 × 10<sup>-2</sup>
  - RRF = 71



- Same data as previous examples
- Considered only  $\lambda_{\text{DU}}$  values
- Increased number of found DU events
- Data based on  $\chi^2$  distribution



Reliability related to # events



### Prior in Use Assessment – summary

- Volume of the operating experience:
  - High observation time -> decrease of FIT
  - Observed events will then contribute less
- Monitoring device performance
  - Better monitoring and documentation -> RRF increases
  - Example 71 -> 117
- Gives a good overview regarding reliability related to observed events



### Prior Use Assessment – Discussion

Can 'certified data' being replaced by 'prior use' data ?

	Certified data	Prior use
Used within green field		1
Used within brown field		
Predictive	1	
Realistic	<b>1</b>	
Cover all SIFs		1
Clear failure data		1
Clear operational data	•	1 · · · · · · · · · · · · · · · · · · ·
Use of historical data		



### **Prior Use Assessment – Discussion**

• Can 'certified data' fully being replaced by 'prior in use' data:

- But....
  - In some cases possible
  - Monitoring device performance during operational phase
  - Predictive to future reliability





## Questions





There's More Than One Terrific Reason to Be Safe at Work



### THEY NEED US



### Back-up slides



### Example 1 – fictitious example

- Failure rate:
  - $\lambda_{DU} = 1 / 500 = 2.00 \times 10^{-3}$  per year = 2.28 x 10<sup>-7</sup> per hour = 228 FIT
  - $\lambda_{DD} = 3/500 = 6.00 \times 10^{-3}$  per year = 6.85 x 10<sup>-7</sup> per hour = 685 FIT
  - $\lambda_{SD} = 2 / 500 = 4.00 \times 10^{-3}$  per year = 4.57 x 10<sup>-7</sup> per hour = 457 FIT
  - $\lambda_{D} = \lambda_{DU} + \lambda_{DD} = 228 + 685 = 913$  FIT
- Calculate  $t_{CE}$   $t_{ce} = \frac{\lambda_{DU}}{\lambda_D} x \left(\frac{T_1}{2} + MTTR\right) + \left(\frac{\lambda_{DD}}{\lambda_D} x MTTR\right)$ 
  - $t_{CE} = (2.28 \times 10^{-7} / 9.13 \times 10^{-7}) * (8760/2 + 5.3) + (6.85 \times 10^{-7} / 9.13 \times 10^{-7} * 5.3)$ = 1.100 + 3.98 = 1104 hours
- Calculate  $PFD_{avg}$   $PFD_{avg} = [(\lambda_{DU}) + (\lambda_{DD})]t_{ce}$ 
  - PFDavg = (2.28 x 10<sup>-7</sup> + 6.85 x 10<sup>-7</sup>) \* 1104 = 5.36 x 10<sup>-4</sup>



### Example 1 – probabilistic example

- $\chi^2[\alpha/2, 2n+2]$ ;  $\alpha/2 = 0.3$  (70% confidense, n = amount of events)
- Failure rate:
  - $\lambda_{DU} = \chi^2 / (2 \times T) = 4.88 / (2 * 500) = 4.88 \times 10^{-3}$  per year = 5.56 × 10<sup>-7</sup> per hour
  - $\lambda_{DD} = \chi^2 / (2 \times T) = 9.52 / (2 \times 500) = 9.52 \times 10^{-3} \text{ per year} = 1.09 \times 10^{-6} \text{ per hour}$
  - $\lambda_{SD} = \chi^2 / (2 \times T) = 7.23 / (2 \times 500) = 7.23 \times 10^{-3} \text{ per year} = 8.25 \times 10^{-7} \text{ per hour}$
  - $\lambda_{\rm D} = \lambda_{\rm DU} + \lambda_{\rm DD} = 2.90 \times 10^{-7} + 5.66 \times 10^{-7} = 8.56 \times 10^{-7}$
- Calculate  $t_{CE}$   $t_{ce} = \frac{\lambda_{DU}}{\lambda_D} x \left(\frac{T_1}{2} + MTTR\right) + \left(\frac{\lambda_{DD}}{\lambda_D} x MTTR\right)$ 
  - $t_{CE} = (5.56 \times 10^{-7} / 1.09 \times 10^{-6}) * (8760/2 + 5.3) + (8.25 \times 10^{-7} / 1.09 \times 10^{-6} * 5.3)$ = 1490 + 3.50 = 1494 hours
- Calculate  $PFD_{avg}$   $PFD_{avg} = [(\lambda_{DU}) + (\lambda_{DD})] t_{ce}$ 
  - $PFD_{avg} = (5.56 \times 10^{-7} + 1.09 \times 10^{-6})^* 1494 = 2.46 \times 10^{-3}$



### Example 2 – probabilistic example

- $\chi^2[\alpha/2, 2n+2]$ ;  $\alpha/2 = 0.3$  (70% confidense, n = amount of events)
- Failure rate:
  - Amount of events (n) = 6
  - $\lambda_{DU} = \chi^2 / (2 \times T) = 4.88 / (2 \times 500) = 1.62 \times 10^{-2} \text{ per year} = 1.85 \times 10^{-6} \text{ per hour}$
- Calculate PFD<sub>avg</sub> for valve
  - PFDavg = 8.11 x 10<sup>-3</sup>
- Calculate PFD<sub>avg</sub> for SIF
  - PFD<sub>avg</sub> = 2.85 × 10<sup>-4</sup> + 4.82 × 10<sup>-4</sup> + 5.30 × 10<sup>-3</sup> + 8.11 × 10<sup>-3</sup>
    - = 1.42 X 10<sup>-2</sup>
  - RRF = 71

